

L Number	Hits	Search Text	DB	Time stamp
1	0	(((((interfer or interfere or interfering or interference or interferometer or interferometric or interferometrically) and (wafer or substrate)) and (spectra or spectrum or spectral)) and thickness) and plasma) and film and periodicity	EPO; JPO; IBM_TDB	2003/12/11 17:59
2	1	(((((interfer or interfere or interfering or interference or interferometer or interferometric or interferometrically) and (wafer or substrate)) and (spectra or spectrum or spectral)) and thickness) and plasma) and film and period\$6	EPO; JPO; IBM_TDB	2003/12/11 17:59
3	5	(((((interfer or interfere or interfering or interference or interferometer or interferometric or interferometrically) and (wafer or substrate)) and (spectra or spectrum or spectral)) and thickness) and plasma) and film	EPO; JPO; IBM_TDB	2003/12/11 17:59
4	6	(((((interfer or interfere or interfering or interference or interferometer or interferometric or interferometrically) and (wafer or substrate)) and (spectra or spectrum or spectral)) and thickness) and plasma) and film	EPO; JPO; IBM_TDB	2003/12/11 18:00
5	96	((interfer or interfere or interfering or interference or interferometer or interferometric or interferometrically) and (wafer or substrate)) and (spectra or spectrum or spectral)) and thickness (356/451).CCLS.	EPO; JPO; IBM_TDB	2003/12/11 18:00
-	243	(356/503).CCLS.	USPAT; US-PGPUB	2003/12/11 11:08
-	140	(356/503).CCLS.	USPAT; US-PGPUB	2003/12/11 10:56
-	541887	interfer or interfere or interfering or interference or interferometer or interferometric or interferometrically	USPAT; US-PGPUB	2003/12/11 11:09
-	629156	wafer or substrate	USPAT; US-PGPUB	2003/12/11 11:09
-	316816	spectra or spectrum or spectral	USPAT; US-PGPUB	2003/12/11 11:09
-	952925	thickness	USPAT; US-PGPUB	2003/12/11 11:09
-	651542	film	USPAT; US-PGPUB	2003/12/11 11:09
-	130563	((interfer or interfere or interfering or interference or interferometer or interferometric or interferometrically) and (wafer or substrate))	USPAT; US-PGPUB	2003/12/11 11:10
-	35342	((interfer or interfere or interfering or interference or interferometer or interferometric or interferometrically) and (wafer or substrate)) and (spectra or spectrum or spectral)	USPAT; US-PGPUB	2003/12/11 11:15
-	17834	((interfer or interfere or interfering or interference or interferometer or interferometric or interferometrically) and (wafer or substrate)) and (spectra or spectrum or spectral)) and thickness	USPAT; US-PGPUB	2003/12/11 18:00
-	194845	plasma	USPAT; US-PGPUB	2003/12/11 11:15
-	5505	(((((interfer or interfere or interfering or interference or interferometer or interferometric or interferometrically) and (wafer or substrate)) and (spectra or spectrum or spectral)) and thickness) and plasma	USPAT; US-PGPUB	2003/12/11 18:00

-	4610	(((((interfer or interfere or interfering or interference or interferometer or interferometric or interferometrically) and (wafer or substrate)) and (spectra or spectrum or spectral)) and thickness) and plasma) and film	USPAT; US-PGPUB	2003/12/11 17:59
-	89	356/450-520.ccls. and (((interfer or interfere or interfering or interference or interferometer or interferometric or interferometrically) and (wafer or substrate)) and (spectra or spectrum or spectral)) and thickness) and plasma	USPAT; US-PGPUB	2003/12/11 11:16
-	3267	(((((interfer or interfere or interfering or interference or interferometer or interferometric or interferometrically) and (wafer or substrate)) and (spectra or spectrum or spectral)) and thickness) and plasma) (((((interfer or interfere or interfering or interference or interferometer or interferometric or interferometrically) and (wafer or substrate)) and (spectra or spectrum or spectral)) and thickness) and plasma) and film and period\$6	USPAT; US-PGPUB	2003/12/11 17:59
-	282	(((((interfer or interfere or interfering or interference or interferometer or interferometric or interferometrically) and (wafer or substrate)) and (spectra or spectrum or spectral)) and thickness) and plasma) and film and periodicity	USPAT; US-PGPUB	2003/12/11 17:59
-	11	356/450-520.ccls. and (((interfer or interfere or interfering or interference or interferometer or interferometric or interferometrically) and (wafer or substrate)) and (spectra or spectrum or spectral)) and thickness) and plasma) and film and periodicity	USPAT; US-PGPUB	2003/12/11 13:48